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Understanding Embedded - FPGAs (Field Programmable Gate Array)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications,

Details

Product Status	Active
Number of LABs/CLBs	18840
Number of Logic Elements/Cells	241152
Total RAM Bits	15335424
Number of I/O	600
Number of Gates	-
Voltage - Supply	0.91V ~ 0.97V
Mounting Type	Surface Mount
Operating Temperature	-40°C ~ 100°C (TJ)
Package / Case	1156-BBGA, FCBGA
Supplier Device Package	1156-FCBGA (35x35)
Purchase URL	https://www.e-xfl.com/product-detail/xilinx/xc6vlx240t-l1ff1156i

Table 4: Typical Quiescent Supply Current (Cont'd)

Symbol	Description	Device	Speed and Temperature Grade						Units
			-3 (C)	-2 (C, E, & I)	-1 (C & I)	-1 (I & M) ⁽²⁾	-1L (C)	-1L (I) ⁽¹⁾	
I_{CC0Q}	Quiescent V_{CC0} supply current	XC6VLX75T	1	1	1	N/A	1	1	mA
		XC6VLX130T	1	1	1	N/A	1	1	mA
		XC6VLX195T	1	1	1	N/A	1	1	mA
		XC6VLX240T	2	2	2	N/A	2	2	mA
		XC6VLX365T	2	2	2	N/A	2	2	mA
		XC6VLX550T ⁽³⁾	N/A	3	3	N/A	3	3	mA
		XC6VLX760 ⁽³⁾	N/A	3	3	N/A	3	3	mA
		XC6VSX315T	2	2	2	N/A	2	2	mA
		XC6VSX475T ⁽³⁾	N/A	2	2	N/A	2	2	mA
		XC6VHX250T	1	1	1	N/A	N/A	N/A	mA
		XC6VHX255T	1	1	1	N/A	N/A	N/A	mA
		XC6VHX380T ⁽⁴⁾	2	2	2	N/A	N/A	N/A	mA
		XC6VHX565T ⁽⁵⁾	N/A	2	2	N/A	N/A	N/A	mA
		XQ6VLX130T	N/A	1	N/A	1	N/A	1	mA
		XQ6VLX240T	N/A	2	N/A	2	N/A	2	mA
		XQ6VLX550T ⁽⁷⁾	N/A	N/A	N/A	3	N/A	3	mA
		XQ6VSX315T	N/A	2	N/A	2	N/A	2	mA
		XQ6VSX475T ⁽⁷⁾	N/A	N/A	N/A	2	N/A	2	mA

Table 4: Typical Quiescent Supply Current (Cont'd)

Symbol	Description	Device	Speed and Temperature Grade						Units
			-3 (C)	-2 (C, E, & I)	-1 (C & I)	-1 (I & M) ⁽²⁾	-1L (C)	-1L (I) ⁽¹⁾	
I_{CCAUXQ}	Quiescent V_{CCAUX} supply current	XC6VLX75T	45	45	45	N/A	45	45	mA
		XC6VLX130T	75	75	75	N/A	75	75	mA
		XC6VLX195T	113	113	113	N/A	113	113	mA
		XC6VLX240T	135	135	135	N/A	135	135	mA
		XC6VLX365T	191	191	191	N/A	191	191	mA
		XC6VLX550T ⁽³⁾	N/A	286	286	N/A	286	286	mA
		XC6VLX760 ⁽³⁾	N/A	387	387	N/A	387	387	mA
		XC6VSX315T	186	186	186	N/A	186	186	mA
		XC6VSX475T ⁽³⁾	N/A	279	279	N/A	279	279	mA
		XC6VHX250T	152	152	152	N/A	N/A	N/A	mA
		XC6VHX255T	152	152	152	N/A	N/A	N/A	mA
		XC6VHX380T ⁽⁴⁾	227	227	227	N/A	N/A	N/A	mA
		XC6VHX565T ⁽⁵⁾	N/A	315	315	N/A	N/A	N/A	mA
		XQ6VLX130T ⁽⁶⁾	N/A	75	N/A	75	N/A	75	mA
		XQ6VLX240T ⁽⁶⁾	N/A	135	N/A	135	N/A	135	mA
		XQ6VLX550T ⁽⁷⁾	N/A	N/A	N/A	286	N/A	286	mA
		XQ6VSX315T ⁽⁶⁾	N/A	186	N/A	186	N/A	186	mA
		XQ6VSX475T ⁽⁷⁾	N/A	N/A	N/A	279	N/A	279	mA

Notes:

1. Typical values are specified at nominal voltage, 85°C junction temperatures (T_j). -1 and -2 industrial (I) grade devices have the same typical values as commercial (C) grade devices at 85°C, but higher values at 100°C. Use the XPE tool to calculate 100°C values. -1L industrial temperature range devices have the values specified in this column.
2. Use the XPE tool to calculate 125°C values for -1M temperature range devices.
3. The -2E extended temperature range ($T_j = 0^\circ\text{C}$ to $+100^\circ\text{C}$) is only available in these devices. The -2I temperature range ($T_j = -40^\circ\text{C}$ to $+100^\circ\text{C}$) is available for all other devices except the XC6VHX565T.
4. The XC6VHX380T is available with both -2E and -2I temperature ranges.
5. The XC6VHX565T is only available in the following temperature ranges: -1C, -1I, -2C, and -2E.
6. The XQ6VLX130T, XQ6VLX240T, and XQ6VSX315T are available in -2I, -1I, -1M, and -1LI temperature ranges.
7. The XQ6VLX550T and the XQ6VSX475T are only available in -1I and -1LI temperature ranges.
8. Typical values are for blank configured devices with no output current loads, no active input pull-up resistors, all I/O pins are 3-state and floating.
9. If DCI or differential signaling is used, more accurate quiescent current estimates can be obtained by using the XPE or XPower Analyzer (XPA) tools.

HT DC Specifications (HT_25)

Table 8: HT DC Specifications

Symbol	DC Parameter	Conditions	Min	Typ	Max	Units
V_{CCO}	Supply Voltage		2.38	2.5	2.63	V
V_{OD}	Differential Output Voltage for XC devices	$R_T = 100 \Omega$ across Q and \bar{Q} signals	480	600	885	mV
	Differential Output Voltage for XQ devices		480	600	930	mV
ΔV_{OD}	Change in V_{OD} Magnitude		-15	-	15	mV
V_{OCM}	Output Common Mode Voltage	$R_T = 100 \Omega$ across Q and \bar{Q} signals	440	600	760	mV
ΔV_{OCM}	Change in V_{OCM} Magnitude		-15	-	15	mV
V_{ID}	Input Differential Voltage		200	600	1000	mV
ΔV_{ID}	Change in V_{ID} Magnitude		-15	-	15	mV
V_{ICM}	Input Common Mode Voltage		440	600	780	mV
ΔV_{ICM}	Change in V_{ICM} Magnitude		-15	-	15	mV

LVDS DC Specifications (LVDS_25)

Table 9: LVDS DC Specifications

Symbol	DC Parameter	Conditions	Min	Typ	Max	Units
V_{CCO}	Supply Voltage		2.38	2.5	2.63	V
V_{OH}	Output High Voltage for Q and \bar{Q}	$R_T = 100 \Omega$ across Q and \bar{Q} signals	-	-	1.675	V
V_{OL}	Output Low Voltage for Q and \bar{Q}	$R_T = 100 \Omega$ across Q and \bar{Q} signals	0.825	-	-	V
V_{ODIFF}	Differential Output Voltage ($Q - \bar{Q}$), Q = High ($\bar{Q} - Q$), \bar{Q} = High	$R_T = 100 \Omega$ across Q and \bar{Q} signals	247	350	600	mV
V_{OCM}	Output Common-Mode Voltage for XC devices	$R_T = 100 \Omega$ across Q and \bar{Q} signals	1.075	1.250	1.425	V
	Output Common-Mode Voltage for XQ devices		1.000	1.250	1.425	V
V_{IDIFF}	Differential Input Voltage ($Q - \bar{Q}$), Q = High ($\bar{Q} - Q$), \bar{Q} = High		100	350	600	mV
V_{ICM}	Input Common-Mode Voltage		0.3	1.2	2.2	V

Extended LVDS DC Specifications (LVDSEXT_25)

Table 10: Extended LVDS DC Specifications

Symbol	DC Parameter	Conditions	Min	Typ	Max	Units
V_{CCO}	Supply Voltage		2.38	2.5	2.63	V
V_{OH}	Output High Voltage for Q and \bar{Q}	$R_T = 100 \Omega$ across Q and \bar{Q} signals	-	-	1.785	V
V_{OL}	Output Low Voltage for Q and \bar{Q}	$R_T = 100 \Omega$ across Q and \bar{Q} signals	0.715	-	-	V
V_{ODIFF}	Differential Output Voltage ($Q - \bar{Q}$), Q = High ($\bar{Q} - Q$), \bar{Q} = High for XC devices	$R_T = 100 \Omega$ across Q and \bar{Q} signals	350	-	840	mV
	Differential Output Voltage ($Q - \bar{Q}$), Q = High ($\bar{Q} - Q$), \bar{Q} = High for XQ devices		350	-	850	mV
V_{OCM}	Output Common-Mode Voltage for XC devices	$R_T = 100 \Omega$ across Q and \bar{Q} signals	1.075	1.250	1.425	V
	Output Common-Mode Voltage for XQ devices		1.000	1.250	1.425	V
V_{IDIFF}	Differential Input Voltage ($Q - \bar{Q}$), Q = High ($\bar{Q} - Q$), \bar{Q} = High	Common-mode input voltage = 1.25V	100	-	1000	mV
V_{ICM}	Input Common-Mode Voltage	Differential input voltage = ± 350 mV	0.3	1.2	2.2	V

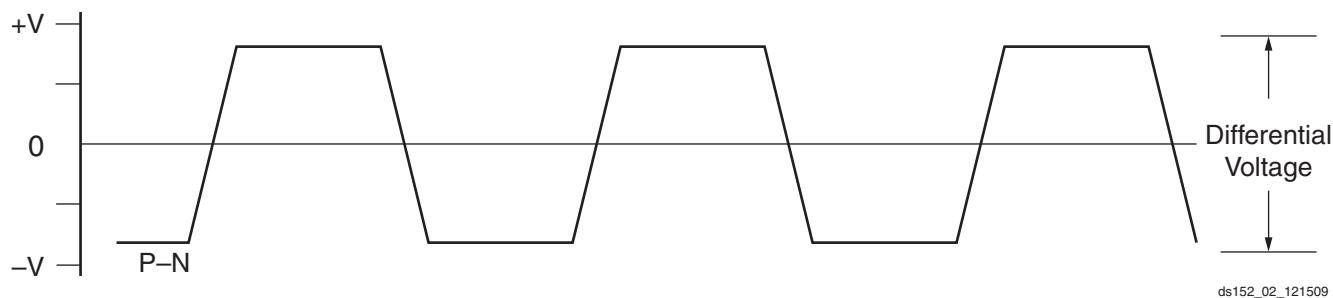


Figure 2: Differential Peak-to-Peak Voltage

Table 18 summarizes the DC specifications of the clock input of the GTX transceiver. Consult [UG366: Virtex-6 FPGA GTX Transceivers User Guide](#) for further details.

Table 18: GTX Transceiver Clock DC Input Level Specification

Symbol	DC Parameter	Min	Typ	Max	Units
V_{IDIFF}	Differential peak-to-peak input voltage	210	800	2000	mV
R_{IN}	Differential input resistance	90	100	130	Ω
C_{EXT}	Required external AC coupling capacitor	–	100	–	nF

GTX Transceiver Switching Characteristics

Consult [UG366: Virtex-6 FPGA GTX Transceivers User Guide](#) for further information.

Table 19: GTX Transceiver Performance

Symbol	Description	Speed Grade				Units
		-3	-2	-1	-1L	
F_{GTXMAX}	Maximum GTX transceiver data rate	6.6	6.6	5.0	5.0	Gb/s
$F_{GPLLMAX}$	Maximum PLL frequency	3.3 ⁽¹⁾	3.3 ⁽¹⁾	2.7	2.7	GHz
$F_{GPLLMIN}$	Minimum PLL frequency	1.2	1.2	1.2	1.2	GHz

Notes:

- See Table 14 for MGTAVCC requirements when PLL frequency is greater than 2.7 GHz.

Table 20: GTX Transceiver Dynamic Reconfiguration Port (DRP) Switching Characteristics

Symbol	Description	Speed Grade				Units
		-3	-2	-1	-1L	
$F_{GTXDRPCLK}$	GTXDRPCLK maximum frequency	150	150	125	100	MHz

Table 24: GTX Transceiver Receiver Switching Characteristics

Symbol	Description		Min	Typ	Max	Units
F_{GTXRX}	Serial data rate	RX oversampler not enabled	0.600	—	F_{GTXMAX}	Gb/s
		RX oversampler enabled	0.480	—	0.600	Gb/s
$T_{RXELECIDLE}$	Time for RXELECIDLE to respond to loss or restoration of data		—	75	—	ns
RX_{OOBVDP}	OOB detect threshold peak-to-peak		60	—	150	mV
RX_{SST}	Receiver spread-spectrum tracking ⁽¹⁾	Modulated @ 33 KHz	-5000	—	0	ppm
RX_{RL}	Run length (CID)	Internal AC capacitor bypassed	—	—	512	UI
RX_{PPMTOL}	Data/REFCLK PPM offset tolerance	CDR 2 nd -order loop disabled	-200	—	200	ppm
		CDR 2 nd -order loop enabled	-2000	—	2000	ppm
SJ Jitter Tolerance⁽²⁾						
$JT_{SJ_{6.5}}$	Sinusoidal Jitter ⁽³⁾	6.5 Gb/s	0.44	—	—	UI
$JT_{SJ_{5.0}}$	Sinusoidal Jitter ⁽³⁾	5.0 Gb/s	0.44	—	—	UI
$JT_{SJ_{4.25}}$	Sinusoidal Jitter ⁽³⁾	4.25 Gb/s	0.44	—	—	UI
$JT_{SJ_{3.75}}$	Sinusoidal Jitter ⁽³⁾	3.75 Gb/s	0.44	—	—	UI
$JT_{SJ_{3.125}}$	Sinusoidal Jitter ⁽³⁾	3.125 Gb/s	0.45	—	—	UI
$JT_{SJ_{3.125L}}$	Sinusoidal Jitter ⁽³⁾	3.125 Gb/s ⁽⁴⁾	0.45	—	—	UI
$JT_{SJ_{2.5}}$	Sinusoidal Jitter ⁽³⁾	2.5 Gb/s ⁽⁵⁾	0.5	—	—	UI
$JT_{SJ_{1.25}}$	Sinusoidal Jitter ⁽³⁾	1.25 Gb/s ⁽⁶⁾	0.5	—	—	UI
$JT_{SJ_{600}}$	Sinusoidal Jitter ⁽³⁾	600 Mb/s	0.4	—	—	UI
$JT_{SJ_{480}}$	Sinusoidal Jitter ⁽³⁾	480 Mb/s	0.4	—	—	UI
SJ Jitter Tolerance with Stressed Eye⁽²⁾						
$JT_{TJSE_{3.125}}$	Total Jitter with Stressed Eye ⁽⁷⁾	3.125 Gb/s	0.70	—	—	UI
		5.0 Gb/s	0.70	—	—	UI
$JT_{SJSE_{3.125}}$	Sinusoidal Jitter with Stressed Eye ⁽⁷⁾	3.125 Gb/s	0.1	—	—	UI
		5.0 Gb/s	0.1	—	—	UI

Notes:

1. Using PLL_RXDIVSEL_OUT = 1, 2, and 4.
2. All jitter values are based on a bit error ratio of $1e^{-12}$.
3. The frequency of the injected sinusoidal jitter is 80 MHz.
4. PLL frequency at 1.5625 GHz and OUTDIV = 1.
5. PLL frequency at 2.5 GHz and OUTDIV = 2.
6. PLL frequency at 2.5 GHz and OUTDIV = 4.
7. Composite jitter with RX equalizer enabled. DFE disabled.

GTH Transceiver Specifications

GTH Transceiver DC Characteristics

Table 25: Absolute Maximum Ratings for GTH Transceivers⁽¹⁾

Symbol	Description	Min	Max	Units
MGTHAVCC	Analog supply voltage for the GTH transmitter, receiver, and common analog circuits	-0.5	1.125	V
MGTHAVCCRX	Analog supply voltage for the GTH receiver circuits and common analog circuits	-0.5	1.125	V
MGTHAVTT	Analog supply voltage for the GTH transmitter termination circuits	-0.5	1.32	V
MGTHAVCCPLL	Analog supply voltage for the GTH receiver and PLL circuits	-0.5	1.935	V
V _{IN}	Receiver (RXP/RXN) and Transmitter (TXP/TXN) absolute input voltage	-0.5	1.125	V
V _{MGTREFCLK}	Reference clock absolute input voltage	-0.5	1.935	V

Notes:

- Stresses beyond those listed under Absolute Maximum Ratings might cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those listed under Operating Conditions is not implied. Exposure to Absolute Maximum Ratings conditions for extended periods of time might affect device reliability.

Table 26: Recommended Operating Conditions for GTH Transceivers⁽¹⁾⁽²⁾

Symbol	Description	Min	Typ	Max	Units
MGTHAVCC	Analog supply voltage for the GTH transmitter, receiver, and common analog circuits	1.075	1.1	1.125	V
MGTHAVCCRX	Analog supply voltage for the GTH receiver circuits and common analog circuits	1.075	1.1	1.125	V
MGTHAVTT	Analog supply voltage for the GTH transmitter termination circuits	1.140	1.2	1.26	V
MGTHAVCCPLL	Analog supply voltage for the GTH receiver and PLL circuit	1.710	1.8	1.89	V

Notes:

- Each voltage listed requires the filter circuit described in [UG371: Virtex-6 FPGA GTH Transceivers User Guide](#).
- Voltages are specified for the temperature range of $T_j = -40^{\circ}\text{C}$ to $+100^{\circ}\text{C}$.

Table 27: GTH Transceiver Power Supply Sequencing⁽¹⁾⁽²⁾⁽³⁾

Symbol	Description	Min	Max	Units
T _{HAVCC2HAVCCRX}	Maximum time between powering MGTHAVCC to when MGTHAVCCRX must be powered.	0	5	ms
T _{HAVCCRX2HAVCCPLL}	Minimum time between powering MGTHAVCCRX to when MGTHAVCCPLL can be powered.	10	–	μs
T _{HAVCCRX2HAVTT}	Minimum time between powering MGTHAVCCRX to when MGTHAVTT can be powered.	10	–	μs

Notes:

- MGTHAVCCRX must be powered simultaneously or within T_{HAVCC2HAVCCRX} of MGTHAVCC, but it must not precede MGTHAVCC.
- MGTHAVCC and MGTHAVCCRX must be powered before MGTHAVCCPLL and MGTHAVTT. This minimum time is defined by T_{HAVCCRX2HAVCCPLL} and T_{HAVCCRX2HAVTT}.
- At any time, the condition of MGTHAVCC being present and MGTHAVCCRX not being present should not occur for more than the maximum T_{HAVCC2HAVCCRX}.

Table 37: GTH Transceiver Receiver Switching Characteristics

Symbol	Description		Min	Typ	Max	Units
R _{XRL}	Run length (CID)		8000	—	—	UI
R _{XPPMTOL}	Data/REFCLK PPM offset tolerance		-200	—	200	ppm
SJ Jitter Tolerance⁽¹⁾⁽²⁾⁽³⁾⁽⁴⁾						
JT_SJ _{11.18}	Sinusoidal Jitter	11.18 Gb/s	0.3	—	—	UI
JT_SJ _{10.32}	Sinusoidal Jitter	10.32 Gb/s	0.3	—	—	UI
JT_SJ _{9.95}	Sinusoidal Jitter	9.95 Gb/s	0.3	—	—	UI
JT_SJ _{2.667}	Sinusoidal Jitter	2.667 Gb/s	0.5	—	—	UI
JT_SJ _{2.48}	Sinusoidal Jitter	2.48 Gb/s	0.5	—	—	UI

Notes:

1. These values are NOT intended for protocol specific compliance determinations.
2. All jitter values are based on a bit error ratio of $1e^{-12}$.
3. The frequency of the injected sinusoidal jitter is 80 MHz.
4. High-frequency jitter tolerance including 6 db of channel loss at a high frequency of the data rate divided by two.

Ethernet MAC Switching Characteristics

Consult [UG368: Virtex-6 FPGA Embedded Tri-mode Ethernet MAC User Guide](#) for further information.

Table 38: Maximum Ethernet MAC Performance

Symbol	Description	Conditions	Speed Grade				Units
			-3	-2	-1	-1L	
F _{TEMACCLIENT}	Client interface maximum frequency	10 Mb/s – 8-bit width	2.5 ⁽¹⁾	2.5 ⁽¹⁾	2.5 ⁽¹⁾	2.5 ⁽¹⁾	MHz
		100 Mb/s – 8-bit width	25 ⁽²⁾	25 ⁽²⁾	25 ⁽²⁾	25 ⁽²⁾	MHz
		1000 Mb/s – 8-bit width	125	125	125	125	MHz
		1000 Mb/s – 16-bit width	62.5	62.5	62.5	62.5	MHz
		2000 Mb/s – 16-bit width	125	125	125	N/A	MHz
		2500 Mb/s – 16-bit width	156.25	156.25	156.25	N/A	MHz
F _{TEMACPHY}	Physical interface maximum frequency	10 Mb/s – 4-bit width	2.5	2.5	2.5	2.5	MHz
		100 Mb/s – 4-bit width	25	25	25	25	MHz
		1000 Mb/s – 8-bit width	125	125	125	125	MHz
		2000 Mb/s – 8-bit width	250	250	250	N/A	MHz
		2500 Mb/s – 8-bit width	312.5	312.5	312.5	N/A	MHz

Notes:

1. When not using clock enable, the F_{MAX} is lowered to 1.25 MHz.
2. When not using clock enable, the F_{MAX} is lowered to 12.5 MHz.

Integrated Interface Block for PCI Express Designs Switching Characteristics

More information and documentation on solutions for PCI Express designs can be found at:
<http://www.xilinx.com/technology/protocols/pciexpress.htm>

Table 39: Maximum Performance for PCI Express Designs

Symbol	Description	Speed Grade				Units
		-3	-2	-1	-1L	
F _{PIPECLK}	Pipe clock maximum frequency	250	250	250	250	MHz
F _{USERCLK}	User clock maximum frequency	500	500	250	250	MHz
F _{DRPCLK}	DRP clock maximum frequency	250	250	250	250	MHz

System Monitor Analog-to-Digital Converter Specification

Table 40: Analog-to-Digital Specifications

Parameter	Symbol	Comments/Conditions	Min	Typ	Max	Units
$AV_{DD} = 2.5V \pm 5\%$, $V_{REFP} = 1.25V$, $V_{REFN} = 0V$, ADCCLK = 5.2 MHz, $T_j = -55^{\circ}C$ to $125^{\circ}C$ M-Grade, Typical values at $T_j=+35^{\circ}C$						
DC Accuracy: All external input channels. Both unipolar and bipolar modes.						
Resolution			10	–	–	Bits
Integral Nonlinearity	INL		–	–	± 1	LSBs
Differential Nonlinearity	DNL	No missing codes (T_{MIN} to T_{MAX}) Guaranteed Monotonic	–	–	± 0.9	LSBs
Unipolar Offset Error ⁽¹⁾		Uncalibrated	–	± 2	± 30	LSBs
Bipolar Offset Error ⁽¹⁾		Uncalibrated measured in bipolar mode	–	± 2	± 30	LSBs
Gain Error		Uncalibrated - External Reference	–	± 0.2	± 2	%
		Uncalibrated - Internal Reference	–	± 2	–	%
Bipolar Gain Error ⁽¹⁾		Uncalibrated - External Reference	–	± 0.2	± 2	%
		Uncalibrated - Internal Reference	–	± 2	–	%
Total Unadjusted Error (Uncalibrated)	TUE	Deviation from ideal transfer function. External 1.25V reference	–	± 10	–	LSBs
		Deviation from ideal transfer function. Internal reference	–	± 20	–	LSBs
Total Unadjusted Error (Calibrated)	TUE	Deviation from ideal transfer function. External 1.25V reference	–	± 1	± 2	LSBs
Calibrated Gain Temperature Coefficient		Variation of FS code with temperature	–	± 0.01	–	LSB/ $^{\circ}C$
DC Common-Mode Reject	CMRR _{DC}	$V_N = V_{CM} = 0.5V \pm 0.5V$, $V_P - V_N = 100mV$	–	70	–	dB
Conversion Rate⁽²⁾						
Conversion Time - Continuous	t _{CONV}	Number of CLK cycles	26	–	32	
Conversion Time - Event	t _{CONV}	Number of CLK cycles	–	–	21	
T/H Acquisition Time	t _{Acq}	Number of CLK cycles	4	–	–	
DRP Clock Frequency	DCLK	DRP clock frequency	8	–	80	MHz
ADC Clock Frequency	ADCCLK	Derived from DCLK	1	–	5.2	MHz
CLK Duty cycle			40	–	60	%

Performance Characteristics

This section provides the performance characteristics of some common functions and designs implemented in Virtex-6 devices. The numbers reported here are worst-case values; they have all been fully characterized. These values are subject to the same guidelines as the [Switching Characteristics, page 26](#).

Table 41: Interface Performances

Description	Speed Grade			
	-3	-2	-1	-1L
Networking Applications				
SDR LVDS transmitter (using OSERDES; DATA_WIDTH = 4 to 8)	710 Mb/s	710 Mb/s	650 Mb/s	585 Mb/s
DDR LVDS transmitter (using OSERDES; DATA_WIDTH = 4 to 10)	1.4 Gb/s	1.3 Gb/s	1.25 Gb/s	1.1 Gb/s
SDR LVDS receiver (SFI-4.1) ⁽¹⁾	710 Mb/s	710 Mb/s	650 Mb/s	585 Mb/s
DDR LVDS receiver (SPI-4.2) ⁽¹⁾	1.4 Gb/s	1.3 Gb/s	1.1 Gb/s	0.9 Gb/s
Maximum Physical Interface (PHY) Rate for Memory Interfaces⁽²⁾⁽³⁾⁽⁴⁾				
DDR2	800 Mb/s	800 Mb/s	800 Mb/s	606 Mb/s
DDR3	1066 Mb/s	1066 Mb/s	800 Mb/s	800 Mb/s
QDR II + SRAM	400 MHz	350 MHz	300 MHz	–
RLDRAM II	500 MHz	400 MHz	350 MHz	–

Notes:

1. LVDS receivers are typically bounded with certain applications where specific DPA algorithms dominate deterministic performance.
2. Verified on Xilinx memory characterization platforms designed according to the guidelines in UG: *Virtex-6 FPGA Memory Interface Solutions User Guide*.
3. Consult [DS186: Virtex-6 FPGA Memory Interface Solutions Data Sheet](#) for performance and feature information on memory interface cores (controller plus PHY).
4. Memory Interface data rates have not been tested over the junction temperature operating range for military (M) temperature devices. Customers are responsible for specifying and testing their specific M temperature grade memory implementation.

Production Silicon and ISE Software Status

In some cases, a particular family member (and speed grade) is released to production before a speed specification is released with the correct label ([Advance](#), [Preliminary](#), [Production](#)). Any labeling discrepancies are corrected in subsequent speed specification releases.

Table 43 lists the production released Virtex-6 family member, speed grade, and the minimum corresponding supported speed specification version and ISE software revisions. The ISE® software and speed specifications listed are the minimum releases required for production. All subsequent releases of software and speed specifications are valid.

Table 43: Virtex-6 Device Production Software and Speed Specification Release

Device	Speed Grade Designations					
	-3	-2	-1	-1L		
XC6VLX75T	ISE 12.2 v1.08			ISE 12.3 v1.07 Patch		
XC6VLX130T	ISE 12.1 v1.06	ISE 11.5 v1.05 ⁽²⁾	ISE 11.5 v1.05 ⁽²⁾	ISE 12.2 v1.05		
XC6VLX195T	ISE 12.1 v1.06	ISE 12.1 v1.06	ISE 12.1 v1.06	ISE 12.2 v1.04		
XC6VLX240T	ISE 12.1 v1.06	ISE 11.4.1 v1.04 ⁽²⁾	ISE 11.4.1 v1.04 ⁽²⁾	ISE 12.2 v1.04		
XC6VLX365T	ISE 12.2 v1.08			ISE 12.2 v1.04		
XC6VLX550T	N/A	ISE 12.2 v1.07		ISE 12.2 v1.04		
XC6VLX760	N/A	ISE 12.2 v1.08		ISE 12.3 v1.07 Patch		
XC6VSX315T	ISE 12.2 v1.08	ISE 12.1 v1.06		ISE 12.3 v1.07 Patch		
XC6VSX475T	N/A	ISE 12.2 v1.08		ISE 12.3 v1.07 Patch		
XC6VHX250T	ISE 12.4 v1.10			N/A		
XC6VHX255T	ISE 13.1 v1.14 using the ISE 13.1 software update			N/A		
XC6VHX380T	ISE 12.4 v1.10			N/A		
XC6VHX565T	N/A	ISE 13.1 v1.14 using the ISE 13.1 software update		N/A		
XQ6VLX130T	N/A	ISE 13.3 v1.17 Patch		ISE 13.3 v1.10		
XQ6VLX240T	N/A	ISE 13.3 v1.17 Patch		ISE 13.3 v1.10		
XQ6VLX550T	N/A	N/A	ISE 13.3 v1.17 Patch	ISE 13.3 v1.10		
XQ6VSX315T	N/A	ISE 13.3 v1.17 Patch		ISE 13.3 v1.10		
XQ6VSX475T	N/A	N/A	ISE 13.3 v1.17 Patch	ISE 13.3 v1.10		

Notes:

1. Blank entries indicate a device and/or speed grade in advance or preliminary status.
2. Designs utilizing the GTX transceivers must use the software version ISE 12.1 v1.06 or later.

Table 44: IOB Switching Characteristics for the Commercial (XC) Virtex-6 Devices (Cont'd)

I/O Standard	T _{IOPI}				T _{IOOP}				T _{IOTP}				Units	
	Speed Grade				Speed Grade				Speed Grade					
	-3	-2	-1	-1L	-3	-2	-1	-1L	-3	-2	-1	-1L		
DIFF_SSTL18_I	0.85	0.94	1.09	1.08	1.47	1.58	1.75	1.73	1.47	1.58	1.75	1.73	ns	
DIFF_SSTL18_I_DCI	0.85	0.94	1.09	1.08	1.40	1.51	1.67	1.65	1.40	1.51	1.67	1.65	ns	
DIFF_SSTL18_II	0.85	0.94	1.09	1.08	1.39	1.50	1.67	1.66	1.39	1.50	1.67	1.66	ns	
DIFF_SSTL18_II_DCI	0.85	0.94	1.09	1.08	1.36	1.47	1.63	1.62	1.36	1.47	1.63	1.62	ns	
DIFF_SSTL18_II_T_DCI	0.85	0.94	1.09	1.08	1.40	1.51	1.67	1.65	1.40	1.51	1.67	1.65	ns	
DIFF_SSTL15	0.81	0.91	1.06	1.06	1.42	1.54	1.71	1.69	1.42	1.54	1.71	1.69	ns	
DIFF_SSTL15_DCI	0.81	0.91	1.06	1.06	1.41	1.52	1.68	1.66	1.41	1.52	1.68	1.66	ns	
DIFF_SSTL15_T_DCI	0.81	0.91	1.06	1.06	1.41	1.52	1.68	1.66	1.41	1.52	1.68	1.66	ns	

Table 45: IOB Switching Characteristics for the Defense-grade (XQ) Virtex-6 Devices

I/O Standard	T _{IOPI}			T _{IOOP}			T _{IOTP}			Units	
	Speed Grade			Speed Grade			Speed Grade				
	-2	-1	-1L	-2	-1	-1L	-2	-1	-1L		
LVDS_25	0.94	1.09	1.08	1.54	2.16	1.62	1.54	2.16	1.62	ns	
LVDSEXT_25	0.94	1.09	1.08	1.65	2.20	1.73	1.65	2.20	1.73	ns	
HT_25	0.94	1.09	1.08	1.62	2.20	1.69	1.62	2.20	1.69	ns	
BLVDS_25	0.94	1.09	1.08	1.50	3.18	1.65	1.50	3.18	1.65	ns	
RSDS_25 (point to point)	0.94	1.09	1.08	1.54	2.22	1.62	1.54	2.22	1.62	ns	
HSTL_I	0.91	1.06	1.06	1.56	2.44	1.71	1.56	2.44	1.71	ns	
HSTL_II	0.91	1.06	1.06	1.56	2.21	1.72	1.56	2.21	1.72	ns	
HSTL_III	0.91	1.06	1.06	1.54	2.50	1.69	1.54	2.50	1.69	ns	
HSTL_I_18	0.91	1.06	1.06	1.58	2.43	1.72	1.58	2.43	1.72	ns	
HSTL_II_18	0.91	1.06	1.06	1.62	2.30	1.78	1.62	2.30	1.78	ns	
HSTL_III_18	0.91	1.06	1.06	1.54	2.49	1.69	1.54	2.49	1.69	ns	
SSTL2_I	0.91	1.06	1.06	1.60	2.50	1.74	1.60	2.50	1.74	ns	
SSTL2_II	0.91	1.06	1.06	1.54	2.49	1.71	1.54	2.49	1.71	ns	
SSTL15	0.91	1.06	1.06	1.54	2.07	1.69	1.54	2.07	1.69	ns	
LVCMOS25, Slow, 2 mA	0.57	0.66	0.70	5.46	6.01	5.63	5.46	6.01	5.63	ns	
LVCMOS25, Slow, 4 mA	0.57	0.66	0.70	3.49	3.79	3.65	3.49	3.79	3.65	ns	
LVCMOS25, Slow, 6 mA	0.57	0.66	0.70	2.81	3.08	2.95	2.81	3.08	2.95	ns	
LVCMOS25, Slow, 8 mA	0.57	0.66	0.70	2.41	2.72	2.59	2.41	2.72	2.59	ns	
LVCMOS25, Slow, 12 mA	0.57	0.66	0.70	1.95	2.23	2.10	1.95	2.23	2.10	ns	
LVCMOS25, Slow, 16 mA	0.57	0.66	0.70	2.05	2.29	2.21	2.05	2.29	2.21	ns	
LVCMOS25, Slow, 24 mA	0.57	0.66	0.70	1.82	2.24	1.98	1.82	2.24	1.98	ns	
LVCMOS25, Fast, 2 mA	0.57	0.66	0.70	5.49	6.04	5.62	5.49	6.04	5.62	ns	
LVCMOS25, Fast, 4 mA	0.57	0.66	0.70	3.50	3.82	3.65	3.50	3.82	3.65	ns	
LVCMOS25, Fast, 6 mA	0.57	0.66	0.70	2.73	2.99	2.88	2.73	2.99	2.88	ns	
LVCMOS25, Fast, 8 mA	0.57	0.66	0.70	2.33	2.65	2.53	2.33	2.65	2.53	ns	
LVCMOS25, Fast, 12 mA	0.57	0.66	0.70	1.88	2.08	2.03	1.88	2.08	2.03	ns	

Table 45: IOB Switching Characteristics for the Defense-grade (XQ) Virtex-6 Devices (Cont'd)

I/O Standard	T _{IOPI}			T _{IOOP}			T _{IOTP}			Units	
	Speed Grade			Speed Grade			Speed Grade				
	-2	-1	-1L	-2	-1	-1L	-2	-1	-1L		
LVCMOS25, Fast, 16 mA	0.57	0.66	0.70	1.92	2.15	2.08	1.92	2.15	2.08	ns	
LVCMOS25, Fast, 24 mA	0.57	0.66	0.70	1.79	2.15	1.96	1.79	2.15	1.96	ns	
LVCMOS18, Slow, 2 mA	0.61	0.71	0.73	4.47	4.87	4.30	4.47	4.87	4.30	ns	
LVCMOS18, Slow, 4 mA	0.61	0.71	0.73	2.96	3.21	2.94	2.96	3.21	2.94	ns	
LVCMOS18, Slow, 6 mA	0.61	0.71	0.73	2.43	2.64	2.47	2.43	2.64	2.47	ns	
LVCMOS18, Slow, 8 mA	0.61	0.71	0.73	2.11	2.41	2.24	2.11	2.41	2.24	ns	
LVCMOS18, Slow, 12 mA	0.61	0.71	0.73	1.99	2.30	2.10	1.99	2.30	2.10	ns	
LVCMOS18, Slow, 16 mA	0.61	0.71	0.73	1.95	2.30	2.04	1.95	2.30	2.04	ns	
LVCMOS18, Fast, 2 mA	0.61	0.71	0.73	4.23	4.57	4.08	4.23	4.57	4.08	ns	
LVCMOS18, Fast, 4 mA	0.61	0.71	0.73	2.76	2.97	2.74	2.76	2.97	2.74	ns	
LVCMOS18, Fast, 6 mA	0.61	0.71	0.73	2.28	2.46	2.32	2.28	2.46	2.32	ns	
LVCMOS18, Fast, 8 mA	0.61	0.71	0.73	1.99	2.34	2.14	1.99	2.34	2.14	ns	
LVCMOS18, Fast, 12 mA	0.61	0.71	0.73	1.80	2.19	1.88	1.80	2.19	1.88	ns	
LVCMOS18, Fast, 16 mA	0.61	0.71	0.73	1.74	2.18	1.88	1.74	2.18	1.88	ns	
LVCMOS15, Slow, 2 mA	0.73	0.85	0.85	3.77	4.29	3.91	3.77	4.29	3.91	ns	
LVCMOS15, Slow, 4 mA	0.73	0.85	0.85	2.79	3.10	2.93	2.79	3.10	2.93	ns	
LVCMOS15, Slow, 6 mA	0.73	0.85	0.85	2.32	2.68	2.50	2.32	2.68	2.50	ns	
LVCMOS15, Slow, 8 mA	0.73	0.85	0.85	1.98	2.29	2.24	1.98	2.29	2.24	ns	
LVCMOS15, Slow, 12 mA	0.73	0.85	0.85	1.91	2.23	2.07	1.91	2.23	2.07	ns	
LVCMOS15, Slow, 16 mA	0.73	0.85	0.85	1.83	2.23	1.98	1.83	2.23	1.98	ns	
LVCMOS15, Fast, 2 mA	0.73	0.85	0.85	3.77	4.28	3.91	3.77	4.28	3.91	ns	
LVCMOS15, Fast, 4 mA	0.73	0.85	0.85	2.53	2.78	2.66	2.53	2.78	2.66	ns	
LVCMOS15, Fast, 6 mA	0.73	0.85	0.85	2.05	2.42	2.16	2.05	2.42	2.16	ns	
LVCMOS15, Fast, 8 mA	0.73	0.85	0.85	1.90	2.20	2.04	1.90	2.20	2.04	ns	
LVCMOS15, Fast, 12 mA	0.73	0.85	0.85	1.77	2.11	1.90	1.77	2.11	1.90	ns	
LVCMOS15, Fast, 16 mA	0.73	0.85	0.85	1.76	2.11	1.92	1.76	2.11	1.92	ns	
LVCMOS12, Slow, 2 mA	0.81	0.93	0.95	3.39	3.75	3.54	3.39	3.75	3.54	ns	
LVCMOS12, Slow, 4 mA	0.81	0.93	0.95	2.63	2.93	2.79	2.63	2.93	2.79	ns	
LVCMOS12, Slow, 6 mA	0.81	0.93	0.95	2.11	2.67	2.26	2.11	2.67	2.26	ns	
LVCMOS12, Slow, 8 mA	0.81	0.93	0.95	2.02	2.25	2.17	2.02	2.25	2.17	ns	
LVCMOS12, Fast, 2 mA	0.81	0.93	0.95	2.98	3.39	3.11	2.98	3.39	3.11	ns	
LVCMOS12, Fast, 4 mA	0.81	0.93	0.95	2.16	2.70	2.31	2.16	2.70	2.31	ns	
LVCMOS12, Fast, 6 mA	0.81	0.93	0.95	1.89	2.34	2.05	1.89	2.34	2.05	ns	
LVCMOS12, Fast, 8 mA	0.81	0.93	0.95	1.82	2.10	1.98	1.82	2.10	1.98	ns	
LVDCI_25	0.57	0.70	0.70	2.14	2.82	2.26	2.14	2.82	2.26	ns	
LVDCI_18	0.61	0.71	0.73	2.23	2.78	2.38	2.23	2.78	2.38	ns	
LVDCI_15	0.73	0.85	0.85	2.01	2.75	2.18	2.01	2.75	2.18	ns	
LVDCI_DV2_25	0.57	0.70	0.70	1.83	2.37	2.00	1.83	2.37	2.00	ns	

Table 45: IOB Switching Characteristics for the Defense-grade (XQ) Virtex-6 Devices (Cont'd)

I/O Standard	T _{IOPI}			T _{IOOP}			T _{IOTP}			Units	
	Speed Grade			Speed Grade			Speed Grade				
	-2	-1	-1L	-2	-1	-1L	-2	-1	-1L		
LVDCI_DV2_18	0.61	0.72	0.73	1.81	2.36	1.98	1.81	2.36	1.98	ns	
LVDCI_DV2_15	0.73	0.85	0.85	1.77	2.30	1.98	1.77	2.30	1.98	ns	
LVPECL_25	0.94	1.09	1.08	1.49	2.68	1.64	1.49	2.68	1.64	ns	
HSTL_I_12	0.91	1.06	1.06	1.60	2.48	1.74	1.60	2.48	1.74	ns	
HSTL_I_DCI	0.91	1.06	1.06	1.50	2.43	1.64	1.50	2.43	1.64	ns	
HSTL_II_DCI	0.91	1.06	1.06	1.49	2.39	1.66	1.49	2.39	1.66	ns	
HSTL_II_T_DCI	0.91	1.06	1.06	1.50	2.43	1.64	1.50	2.43	1.64	ns	
HSTL_III_DCI	0.91	1.06	1.06	1.45	2.48	1.61	1.45	2.48	1.61	ns	
HSTL_I_DCI_18	0.91	1.06	1.06	1.53	2.44	1.66	1.53	2.44	1.66	ns	
HSTL_II_DCI_18	0.91	1.06	1.06	1.46	2.41	1.59	1.46	2.41	1.59	ns	
HSTL_II_T_DCI_18	0.91	1.06	1.06	1.53	2.43	1.66	1.53	2.43	1.66	ns	
HSTL_III_DCI_18	0.91	1.06	1.06	1.54	2.50	1.67	1.54	2.50	1.67	ns	
DIFF_HSTL_I_18	0.94	1.09	1.08	1.58	2.30	1.72	1.58	2.30	1.72	ns	
DIFF_HSTL_I_DCI_18	0.94	1.09	1.08	1.53	2.21	1.66	1.53	2.21	1.66	ns	
DIFF_HSTL_I	0.94	1.09	1.08	1.56	2.28	1.71	1.56	2.28	1.71	ns	
DIFF_HSTL_I_DCI	0.94	1.09	1.08	1.50	2.28	1.64	1.50	2.28	1.64	ns	
DIFF_HSTL_II_18	0.94	1.09	1.08	1.62	2.33	1.78	1.62	2.33	1.78	ns	
DIFF_HSTL_II_DCI_18	0.94	1.09	1.08	1.46	2.18	1.59	1.46	2.18	1.59	ns	
DIFF_HSTL_II_T_DCI_18	0.94	1.09	1.08	1.53	2.22	1.66	1.53	2.22	1.66	ns	
DIFF_HSTL_II	0.94	1.09	1.08	1.56	2.29	1.72	1.56	2.29	1.72	ns	
DIFF_HSTL_II_DCI	0.94	1.09	1.08	1.49	2.26	1.66	1.49	2.26	1.66	ns	
SSTL2_I_DCI	0.91	1.06	1.06	1.53	2.51	1.68	1.53	2.51	1.68	ns	
SSTL2_II_DCI	0.91	1.06	1.06	1.50	2.50	1.69	1.50	2.50	1.69	ns	
SSTL2_II_T_DCI	0.91	1.06	1.06	1.53	2.52	1.68	1.53	2.52	1.68	ns	
SSTL18_I	0.91	1.06	1.06	1.58	2.48	1.73	1.58	2.48	1.73	ns	
SSTL18_II	0.91	1.06	1.06	1.50	2.46	1.66	1.50	2.46	1.66	ns	
SSTL18_I_DCI	0.91	1.06	1.06	1.51	2.49	1.65	1.51	2.49	1.65	ns	
SSTL18_II_DCI	0.91	1.06	1.06	1.47	2.41	1.62	1.47	2.41	1.62	ns	
SSTL18_II_T_DCI	0.91	1.06	1.06	1.51	2.49	1.65	1.51	2.49	1.65	ns	
SSTL15_T_DCI	0.91	1.06	1.06	1.52	2.48	1.66	1.52	2.48	1.66	ns	
SSTL15_DCI	0.91	1.06	1.06	1.52	2.48	1.66	1.52	2.48	1.66	ns	
DIFF_SSTL2_I	0.94	1.09	1.08	1.60	2.34	1.74	1.60	2.34	1.74	ns	
DIFF_SSTL2_I_DCI	0.94	1.09	1.08	1.53	2.25	1.68	1.53	2.25	1.68	ns	
DIFF_SSTL2_II	0.94	1.09	1.08	1.54	2.29	1.71	1.54	2.29	1.71	ns	
DIFF_SSTL2_II_DCI	0.94	1.09	1.08	1.50	2.23	1.69	1.50	2.23	1.69	ns	
DIFF_SSTL2_II_T_DCI	0.94	1.09	1.08	1.53	2.26	1.68	1.53	2.26	1.68	ns	
DIFF_SSTL18_I	0.94	1.09	1.08	1.58	2.22	1.73	1.58	2.22	1.73	ns	
DIFF_SSTL18_I_DCI	0.94	1.09	1.08	1.51	2.30	1.65	1.51	2.30	1.65	ns	

Table 48: Output Delay Measurement Methodology (Cont'd)

Description	I/O Standard Attribute	R _{REF} (Ω)	C _{REF} ⁽¹⁾ (pF)	V _{MEAS} (V)	V _{REF} (V)
HT (HyperTransport), 2.5V	LDT_25	100	0	0 ⁽²⁾	0.6
LVPECL (Low-Voltage Positive Emitter-Coupled Logic), 2.5V	LVPECL_25	100	0	0 ⁽²⁾	0
LVDCI/HSLVDCI, 2.5V	LVDCI_25, HSLVDCI_25	1M	0	1.25	0
LVDCI/HSLVDCI, 1.8V	LVDCI_18, HSLVDCI_18	1M	0	0.9	0
LVDCI/HSLVDCI, 1.5V	LVDCI_15, HSLVDCI_15	1M	0	0.75	0
HSTL (High-Speed Transceiver Logic), Class I & II, with DCI	HSTL_I_DC1, HSTL_II_DC1	50	0	V _{REF}	0.75
HSTL, Class III, with DCI	HSTL_III_DC1	50	0	0.9	1.5
HSTL, Class I & II, 1.8V, with DCI	HSTL_I_DC1_18, HSTL_II_DC1_18	50	0	V _{REF}	0.9
HSTL, Class III, 1.8V, with DCI	HSTL_III_DC1_18	50	0	1.1	1.8
SSTL (Stub Series Termination Logic), Class I & II, 1.8V, with DCI	SSTL18_I_DC1, SSTL18_II_DC1	50	0	V _{REF}	0.9
SSTL, Class I & II, 2.5V, with DCI	SSTL2_I_DC1, SSTL2_II_DC1	50	0	V _{REF}	1.25

Notes:

1. C_{REF} is the capacitance of the probe, nominally 0 pF.
2. The value given is the differential output voltage.

Input/Output Logic Switching Characteristics

Table 49: ILOGIC Switching Characteristics

Symbol	Description	Speed Grade				Units
		-3	-2	-1	-1L	
Setup/Hold						
T _{ICE1CK/TICKCE1}	CE1 pin Setup/Hold with respect to CLK	0.21/ 0.03	0.25/ 0.04	0.27/ 0.04	0.31/ 0.05	ns
T _{ISRCK/TICKSR}	SR pin Setup/Hold with respect to CLK	0.66/ -0.08	0.78/ -0.08	0.96/ -0.08	1.09/ -0.11	ns
T _{IDOCK/TILOCKD}	D pin Setup/Hold with respect to CLK without Delay	0.07/ 0.41	0.08/ 0.46	0.10/ 0.54	0.11/ 0.64	ns
T _{IDOCKD/TILOCKDD}	DDLY pin Setup/Hold with respect to CLK (using IODELAY)	0.10/ 0.32	0.12/ 0.36	0.14/ 0.42	0.16/ 0.50	ns
Combinatorial						
T _{IDI}	D pin to O pin propagation delay, no Delay	0.15	0.17	0.20	0.23	ns
T _{IDID}	DDLY pin to O pin propagation delay (using IODELAY)	0.19	0.22	0.25	0.28	ns
Sequential Delays						
T _{IDLO}	D pin to Q1 pin using flip-flop as a latch without Delay	0.48	0.54	0.64	0.73	ns
T _{IDLOD}	DDLY pin to Q1 pin using flip-flop as a latch (using IODELAY)	0.52	0.58	0.68	0.78	ns
T _{ICKQ}	CLK to Q outputs	0.54	0.61	0.70	0.93	ns
T _{RQ_ILOGIC}	SR pin to OQ/TQ out	0.85	0.97	1.15	1.32	ns
T _{GSRQ_ILOGIC}	Global Set/Reset to Q outputs	7.60	7.60	10.51	10.51	ns
Set/Reset						
T _{RPW_ILOGIC}	Minimum Pulse Width, SR inputs	0.78	0.95	1.20	1.30	ns, Min

Input Serializer/Deserializer Switching Characteristics

Table 51: ISERDES Switching Characteristics

Symbol	Description	Speed Grade					Units
		-3	-2	-1 (XC)	-1 (XQ)	-1L	
Setup/Hold for Control Lines							
T _{ISCKC_BITSILIP} / T _{ISCKC_BITSILIP}	BITSLIP pin Setup/Hold with respect to CLKDIV	0.07/ 0.15	0.08/ 0.16	0.09/ 0.17	0.09/ 0.17	0.14/ 0.17	ns
T _{ISCKC_CE} / T _{ISCKC_CE} ⁽²⁾	CE pin Setup/Hold with respect to CLK (for CE1)	0.20/ 0.03	0.25/ 0.04	0.27/ 0.04	0.27/ 0.04	0.31/ 0.05	ns
T _{ISCKC_CE2} / T _{ISCKC_CE2} ⁽²⁾	CE pin Setup/Hold with respect to CLKDIV (for CE2)	0.01/ 0.27	0.01/ 0.29	0.01/ 0.31	0.01/ 0.31	-0.05/ 0.35	ns
Setup/Hold for Data Lines							
T _{ISDCK_D} / T _{ISCKD_D}	D pin Setup/Hold with respect to CLK	0.07/ 0.08	0.08/ 0.09	0.09/ 0.11	0.09/ 0.11	0.11/ 0.19	ns
T _{ISDCK_DDLY} / T _{ISCKD_DDLY}	DDLY pin Setup/Hold with respect to CLK (using IODELAY) ⁽¹⁾	0.10/ 0.05	0.12/ 0.06	0.14/ 0.07	0.14/ 0.07	0.16/ 0.15	ns
T _{ISDCK_D_DDR} / T _{ISCKD_D_DDR}	D pin Setup/Hold with respect to CLK at DDR mode	0.07/ 0.08	0.08/ 0.09	0.09/ 0.11	0.09/ 0.11	0.11/ 0.19	ns
T _{ISDCK_DDLY_DDR} T _{ISCKD_DDLY_DDR}	D pin Setup/Hold with respect to CLK at DDR mode (using IODELAY) ⁽¹⁾	0.10/ 0.05	0.12/ 0.06	0.14/ 0.07	0.14/ 0.07	0.16/ 0.15	ns
Sequential Delays							
T _{ISCKO_Q}	CLKDIV to out at Q pin	0.57	0.66	0.75	0.80	0.88	ns
Propagation Delays							
T _{ISDO_DO}	D input to DO output pin	0.19	0.22	0.25	0.25	0.28	ns

Notes:

1. Recorded at 0 tap value.
2. T_{ISCKC_CE2} and T_{ISCKC_CE2} are reported as T_{ISCKC_CE}/T_{ISCKC_CE} in TRACE report.

CLB Distributed RAM Switching Characteristics (SLICEM Only)

Table 55: CLB Distributed RAM Switching Characteristics

Symbol	Description	Speed Grade				Units
		-3	-2	-1	-1L	
Sequential Delays						
T _{SHCKO}	Clock to A – B outputs	0.92	1.10	1.36	1.49	ns, Max
T _{SHCKO_1}	Clock to AMUX – BMUX outputs	1.19	1.40	1.71	1.87	ns, Max
Setup and Hold Times Before/After Clock CLK						
T _{DS/T_{DH}}	A – D inputs to CLK	0.62/0.18	0.72/0.20	0.88/0.22	0.98/0.23	ns, Min
T _{AS/T_{AH}}	Address An inputs to clock	0.19/0.52	0.22/0.59	0.27/0.66	0.30/0.75	ns, Min
T _{WS/T_{WH}}	WE input to clock	0.27/0.00	0.32/0.00	0.40/0.00	0.47–0.03	ns, Min
T _{CECK/T_{CKCE}}	CE input to CLK	0.28–0.01	0.34–0.01	0.41–0.01	0.48–0.05	ns, Min
Clock CLK						
T _{MPW}	Minimum pulse width	0.70	0.82	1.00	1.04	ns, Min
T _{MCP}	Minimum clock period	1.40	1.64	2.00	2.08	ns, Min

Notes:

1. A Zero “0” Hold Time listing indicates no hold time or a negative hold time. Negative values cannot be guaranteed “best-case”, but if a “0” is listed, there is no positive hold time.
2. T_{SHCKO} also represents the CLK to XMUX output. Refer to TRACE report for the CLK to XMUX path.

CLB Shift Register Switching Characteristics (SLICEM Only)

Table 56: CLB Shift Register Switching Characteristics

Symbol	Description	Speed Grade				Units
		-3	-2	-1	-1L	
Sequential Delays						
T _{REG}	Clock to A – D outputs	1.11	1.30	1.58	1.74	ns, Max
T _{REG_MUX}	Clock to AMUX – DMUX output	1.37	1.60	1.93	2.12	ns, Max
T _{REG_M31}	Clock to DMUX output via M31 output	1.08	1.27	1.55	1.74	ns, Max
Setup and Hold Times Before/After Clock CLK						
T _{WS/T_{WH}}	WE input	0.05/0.00	0.07/0.00	0.09/0.00	0.11/0.03	ns, Min
T _{CECK/T_{CKCE}}	CE input to CLK	0.06–0.01	0.08–0.01	0.10–0.01	0.12/0.02	ns, Min
T _{DS/T_{DH}}	A – D inputs to CLK	0.64/0.18	0.76/0.21	0.94/0.24	1.07/0.23	ns, Min
Clock CLK						
T _{MPW}	Minimum pulse width	0.60	0.70	0.85	0.89	ns, Min

Notes:

1. A Zero “0” Hold Time listing indicates no hold time or a negative hold time. Negative values cannot be guaranteed “best-case”, but if a “0” is listed, there is no positive hold time.

Table 58: DSP48E1 Switching Characteristics (Cont'd)

Symbol	Description	Speed Grade					Units
		-3	-2	-1 (XC)	-1 (XQ)	-1L	
Maximum Frequency							
F _{MAX}	With all registers used	600	540	450	450	410	MHz
F _{MAX_PATDET}	With pattern detector	551	483	408	408	356	MHz
F _{MAX_MULT_NOMREG}	Two register multiply without MREG	356	311	262	262	224	MHz
F _{MAX_MULT_NOMREG_PATDET}	Two register multiply without MREG with pattern detect	327	286	241	241	211	MHz
F _{MAX_PREADD_MULT_NOADREG}	Without ADREG	398	347	292	292	254	MHz
F _{MAX_PREADD_MULT_NOADREG_PATDET}	Without ADREG with pattern detect	398	347	292	292	254	MHz
F _{MAX_NOPIPELINEREG}	Without pipeline registers (MREG, ADREG)	266	233	196	196	171	MHz
F _{MAX_NOPIPELINEREG_PATDET}	Without pipeline registers (MREG, ADREG) with pattern detect	250	219	184	184	160	MHz

Configuration Switching Characteristics

Table 59: Configuration Switching Characteristics

Symbol	Description	Speed Grade				Units
		-3	-2	-1	-1L	
Power-up Timing Characteristics						
T _{PL} ⁽¹⁾	Program Latency	5	5	5	5	ms, Max
T _{POR} ⁽¹⁾	Power-on-Reset	15/55	15/55	15/55	15/60	ms, Min/Max
T _{CCLK}	CCLK (output) delay	400	400	400	400	ns, Min
T _{PROGRAM}	Program Pulse Width	250	250	250	250	ns, Min
Master/Slave Serial Mode Programming Switching						
T _{DCCK/T_{CCKD}}	DIN Setup/Hold, slave mode	4.0/0.0	4.0/0.0	4.0/0.0	4.5/0.0	ns, Min
T _{DSCCK/T_{SCCKD}}	DIN Setup/Hold, master mode	4.0/0.0	4.0/0.0	4.0/0.0	5.0/0.0	ns, Min
T _{CCO}	DOUT at 2.5V	6	6	6	7	ns, Max
	DOUT at 1.8V	6	6	6	7	ns, Max
F _{MCCK}	Maximum CCLK frequency, serial modes	105	105	105	70	MHz, Max
F _{MCCKTOL}	Frequency Tolerance, master mode with respect to nominal CCLK.	55	55	55	60	%
F _{MSCK}	Slave mode external CCLK	100	100	100	100	MHz
SelectMAP Mode Programming Switching						
T _{SMDCK/T_{SMCKD}}	SelectMAP Data Setup/Hold	4.0/0.0	4.0/0.0	4.0/0.0	5.5/0.0	ns, Min
T _{SMCSCCK/T_{SMCKCS}}	CSI_B Setup/Hold	4.0/0.0	4.0/0.0	4.0/0.0	5.5/0.0	ns, Min
T _{SMCKW/T_{SMWCK}}	RDWR_B Setup/Hold	10.0/0.0	10.0/0.0	10.0/0.0	16.0/0.0	ns, Min
T _{SMCKCSO}	CSO_B clock to out (330 Ω pull-up resistor required)	6	6	6	7	ns, Max
T _{SMCO}	CCLK to DATA out in readback at 2.5V	6	6	6	7	ns, Max
	CCLK to DATA out in readback at 1.8V	6	6	6	7	ns, Max

Table 69: Global Clock Input Setup and Hold With MMCM

Symbol	Description	Device	Speed Grade				Units
			-3	-2	-1	-1L	
Input Setup and Hold Time Relative to Global Clock Input Signal for LVCMS25 Standard.⁽¹⁾							
T _{PSMMC} MG _C /T _{PHMMC} MG _C	No Delay Global Clock Input and IFF ⁽²⁾ with MMCM	XC6VLX75T	1.45/ -0.18	1.57/ -0.18	1.72/ -0.18	1.78/ -0.08	ns
		XC6VLX130T	1.53/ -0.18	1.65/ -0.18	1.81/ -0.18	1.87/ -0.07	ns
		XC6VLX195T	1.54/ -0.17	1.66/ -0.17	1.82/ -0.17	1.87/ -0.08	ns
		XC6VLX240T	1.54/ -0.17	1.66/ -0.17	1.82/ -0.17	1.87/ -0.08	ns
		XC6VLX365T	1.55/ -0.18	1.67/ -0.18	1.83/ -0.18	1.87/ -0.07	ns
		XC6VLX550T	N/A	1.84/ -0.17	2.02/ -0.17	2.06/ -0.06	ns
		XC6VLX760	N/A	2.26/ -0.13	2.49/ -0.13	2.06/ -0.03	ns
		XC6VSX315T	1.56/ -0.18	1.68/ -0.18	1.84/ -0.18	1.89/ -0.08	ns
		XC6VSX475T	N/A	1.85/ -0.23	2.03/ -0.23	2.07/ -0.13	ns
		XC6VHX250T	1.52/ -0.17	1.64/ -0.17	1.80/ -0.17	N/A	ns
		XC6VHX255T	1.52/ -0.12	1.64/ -0.12	1.85/ -0.12	N/A	ns
		XC6VHX380T	1.68/ -0.16	1.81/ -0.16	1.99/ -0.16	N/A	ns
		XC6VHX565T	N/A	1.81/ -0.01	1.99/ -0.01	N/A	ns
		XQ6VLX130T	N/A	1.65/ -0.18	1.81/ -0.18	1.87/ -0.07	ns
		XQ6VLX240T	N/A	1.66/ -0.17	1.82/ -0.17	1.87/ -0.08	ns
		XQ6VLX550T	N/A	N/A	2.02/ -0.17	2.06/ -0.06	ns
		XQ6VSX315T	N/A	1.68/ -0.18	1.84/ -0.18	1.89/ -0.08	ns
		XQ6VSX475T	N/A	N/A	2.03/ -0.23	2.07/ -0.13	ns

Notes:

1. Setup and Hold times are measured over worst case conditions (process, voltage, temperature). Setup time is measured relative to the Global Clock input signal using the slowest process, highest temperature, and lowest voltage. Hold time is measured relative to the Global Clock input signal using the fastest process, lowest temperature, and highest voltage.
2. IFF = Input Flip-Flop or Latch
3. Use IBIS to determine any duty-cycle distortion incurred using various standards.

Table 70: Clock-Capable Clock Input Setup and Hold With MMCM

Symbol	Description	Device	Speed Grade				Units
			-3	-2	-1	-1L	
Input Setup and Hold Time Relative to Clock-capable Clock Input Signal for LVCMS25 Standard.⁽¹⁾							
T _{PSMMC} /T _{PHMMC}	No Delay Clock-capable Clock Input and IFF ⁽²⁾ with MMCM	XC6VLX75T	1.56/ -0.25	1.69/ -0.25	1.86/ -0.25	1.91/ -0.15	ns
		XC6VLX130T	1.64/ -0.25	1.78/ -0.25	1.95/ -0.25	2.00/ -0.14	ns
		XC6VLX195T	1.65/ -0.24	1.79/ -0.24	1.96/ -0.24	2.01/ -0.15	ns
		XC6VLX240T	1.65/ -0.24	1.79/ -0.24	1.96/ -0.24	2.01/ -0.15	ns
		XC6VLX365T	1.66/ -0.25	1.79/ -0.25	1.97/ -0.25	2.02/ -0.15	ns
		XC6VLX550T	N/A	1.97/ -0.24	2.16/ -0.24	2.19/ -0.14	ns
		XC6VLX760	N/A	2.39/ -0.20	2.63/ -0.20	2.21/ -0.10	ns
		XC6VSX315T	1.67/ -0.25	1.80/ -0.25	1.98/ -0.25	2.03/ -0.16	ns
		XC6VSX475T	N/A	1.98/ -0.29	2.17/ -0.29	2.21/ -0.20	ns
		XC6VHX250T	1.63/ -0.24	1.76/ -0.24	1.94/ -0.24	N/A	ns
		XC6VHX255T	1.63/ -0.19	1.76/ -0.19	1.99/ -0.19	N/A	ns
		XC6VHX380T	1.80/ -0.23	1.94/ -0.23	2.13/ -0.23	N/A	ns
		XC6VHX565T	N/A	1.94/ -0.08	2.13/ -0.08	N/A	ns
		XQ6VLX130T	N/A	1.78/ -0.25	1.95/ -0.25	2.00/ -0.14	ns
		XQ6VLX240T	N/A	1.79/ -0.24	1.96/ -0.24	2.01/ -0.15	ns
		XQ6VLX550T	N/A	N/A	2.16/ -0.24	2.19/ -0.14	ns
		XQ6VSX315T	N/A	1.80/ -0.25	1.98/ -0.25	2.03/ -0.16	ns
		XQ6VSX475T	N/A	N/A	2.17/ -0.29	2.21/ -0.20	ns

Notes:

1. Setup and Hold times are measured over worst case conditions (process, voltage, temperature). Setup time is measured relative to the Global Clock input signal using the slowest process, highest temperature, and lowest voltage. Hold time is measured relative to the Global Clock input signal using the fastest process, lowest temperature, and highest voltage.
2. IFF = Input Flip-Flop or Latch
3. Use IBIS to determine any duty-cycle distortion incurred using various standards.

Table 73: Sample Window

Symbol	Description	Device	Speed Grade				Units
			-3	-2	-1	-1L	
T _{SAMP}	Sampling Error at Receiver Pins ⁽¹⁾	All	510	560	610	670	ps
T _{SAMP_BUFI0}	Sampling Error at Receiver Pins using BUFI0 ⁽²⁾	All	300	350	400	440	ps

Notes:

1. This parameter indicates the total sampling error of Virtex-6 FPGA DDR input registers, measured across voltage, temperature, and process. The characterization methodology uses the MMCM to capture the DDR input registers' edges of operation. These measurements include:
 - CLK0 MMCM jitter
 - MMCM accuracy (phase offset)
 - MMCM phase shift resolution
 These measurements do not include package or clock tree skew.
2. This parameter indicates the total sampling error of Virtex-6 FPGA DDR input registers, measured across voltage, temperature, and process. The characterization methodology uses the BUFI0 clock network and IODELAY to capture the DDR input registers' edges of operation. These measurements do not include package or clock tree skew.

Table 74: Pin-to-Pin Setup/Hold and Clock-to-Out

Symbol	Description	Speed Grade				Units
		-3	-2	-1	-1L	
Data Input Setup and Hold Times Relative to a Forwarded Clock Input Pin Using BUFI0						
T _{PSCS/T_{PHCS}}	Setup/Hold of I/O clock	-0.28/1.09	-0.28/1.16	-0.28/1.33	-0.18/1.79	ns
Pin-to-Pin Clock-to-Out Using BUFI0						
T _{CLOCKOFCS}	Clock-to-Out of I/O clock	4.22	4.59	5.22	5.63	ns

Revision History

The following table shows the revision history for this document:

Date	Version	Description of Revisions
06/24/09	1.0	Initial Xilinx release.
07/16/09	1.1	Revised the maximum V _{CCAUX} and V _{IN} numbers in Table 2, page 2 . Removed empty column from Table 3, page 3 . Revised specifications on Table 20, page 13 . Updated Table 38, page 22 and added notes 1 and 2. Revised T _{DLYCCO_RDY} , T _{IDELAYCTRL_RPW} , and T _{IDELAYPAT_JIT} in Table 53, page 41 . Updated Table 58, page 46 to more closely match the DSP48E1 speed specifications. Updated T _{TAPTCK/TCKTAP} in Table 59, page 49 . Updated XC6VLX130T parameters in Table 68 through Table 70, page 59 .
08/19/09	1.2	Added values for -1L voltages and speed grade in all pertinent tables. Added V _{FS} and notes to Table 1 and Table 2 . Removed DV _{PPIN} from the example in Figure 2 . Added networking applications to Table 41, page 25 . Changed and added to the block RAM F _{MAX} section in Table 57, page 44 including removing Note 12. Changed F _{PFDMAX} values and corrected units for T _{STATPHAOFFSET} and T _{OUTDUTY} in Table 64, page 52 . Updated Table 71, page 60 .
09/16/09	2.0	Added Virtex-6 HXT devices to entire document including GTH Transceiver Specifications . Updated speed specifications as described in Switching Characteristics , includes changes in Table 51 , Table 57 , Table 58 , and Table 66 through Table 70 . Comprehensive changes to Table 14 , Table 15 , and Table 16 . Added conditions to DV _{PPOUT} and revised description of T _{OSKEW} in Table 17 . Removed V _{ISE} specification and note from Table 18 . Added note 3 to Table 23 . Updated note 3 in Table 24 . Updated LVCMOS25 delays in Table 44 . Updated specification for T _{IOTPHZ} in Table 46 . Removed T _{BUFHSKREW} from Table 71, page 60 and added values for T _{BUFIOSKEW} . Added values in Table 74 .